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APPLICATION NO.	PLICATION NO. FILING DATE		FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.
09/925,512	09/925,512 08/10/2001		Hideto Ohnuma	12732-068001	4989
26171	7590	04/13/2005		EXAMINER	
FISH & RI			BOOTH, RICHARD A		
1425 K STR 11TH FLOC	-	<i>/</i> .		ART UNIT	PAPER NUMBER
WASHING	WASHINGTON, DC 20005-3500			2812	
				DATE MAILED: 04/13/200	5

Please find below and/or attached an Office communication concerning this application or proceeding.

	Application No.	Applicant(s)	(m)
	09/925,512	OHNUMA ET AL.	(C)
Office Action Summary	Examiner	Art Unit	
	Richard A. Booth	2812	
The MAILING DATE of this communication app Period for Reply	pears on the cover sheet t	with the correspondence addres	SS
A SHORTENED STATUTORY PERIOD FOR REPL THE MAILING DATE OF THIS COMMUNICATION. - Extensions of time may be available under the provisions of 37 CFR 1.1 after SIX (6) MONTHS from the mailing date of this communication. - If the period for reply specified above is less than thirty (30) days, a repl - If NO period for reply is specified above, the maximum statutory period - Failure to reply within the set or extended period for reply will, by statute Any reply received by the Office later than three months after the mailing earned patent term adjustment. See 37 CFR 1.704(b).	36(a). In no event, however, may a y within the statutory minimum of the will apply and will expire SIX (6) MC, cause the application to become a	a reply be timely filed nirty (30) days will be considered timely. DNTHS from the mailing date of this commu ABANDONED (35 U.S.C. § 133).	inication.
Status			
1) ☐ Responsive to communication(s) filed on <u>01 F</u> 2a) ☐ This action is FINAL. 2b) ☐ This 3) ☐ Since this application is in condition for alloware closed in accordance with the practice under E	s action is non-final. nce except for formal ma	•	erits is
Disposition of Claims			
4) ☑ Claim(s) 1,4,11,14,18,21,32,33,35,36,52,53,56 4a) Of the above claim(s) is/are withdray 5) ☐ Claim(s) is/are allowed. 6) ☑ Claim(s) 1,4,11,14,18,21,32,33,35,36,52,53,56 7) ☐ Claim(s) is/are objected to. 8) ☐ Claim(s) are subject to restriction and/or	wn from consideration. 5 <u>,58,65-78 and 86-102</u> is		
Application Papers			
9) The specification is objected to by the Examine 10) The drawing(s) filed on is/are: a) accomplicant may not request that any objection to the Replacement drawing sheet(s) including the correct 11) The oath or declaration is objected to by the Examine	epted or b) objected to drawing(s) be held in abeya tion is required if the drawin	ance. See 37 CFR 1.85(a). ng(s) is objected to. See 37 CFR 1	, ,
Priority under 35 U.S.C. § 119			
 12) Acknowledgment is made of a claim for foreign a) All b) Some * c) None of: 1. Certified copies of the priority document 2. Certified copies of the priority document 3. Copies of the certified copies of the priority application from the International Burea * See the attached detailed Office action for a list 	s have been received. s have been received in nty documents have bee u (PCT Rule 17.2(a)).	Application No In received in this National Sta	ge
Attachment(s)			
1) Notice of References Cited (PTO-892) 2) Notice of Draftsperson's Patent Drawing Review (PTO-948) 3) Information Disclosure Statement(s) (PTO-1449 or PTO/SB/08) Paper No(s)/Mail Date	Paper No	v Summary (PTO-413) o(s)/Mail Date f Informal Patent Application (PTO-152	2)

DETAILED ACTION

Continued Examination Under 37 CFR 1.114

A request for continued examination under 37 CFR 1.114, including the fee set forth in 37 CFR 1.17(e), was filed in this application after final rejection. Since this application is eligible for continued examination under 37 CFR 1.114, and the fee set forth in 37 CFR 1.17(e) has been timely paid, the finality of the previous Office action has been withdrawn pursuant to 37 CFR 1.114. Applicant's submission filed on 2/1/05 has been entered.

Claim Rejections - 35 USC § 103

The following is a quotation of 35 U.S.C. 103(a) which forms the basis for all obviousness rejections set forth in this Office action:

(a) A patent may not be obtained though the invention is not identically disclosed or described as set forth in section 102 of this title, if the differences between the subject matter sought to be patented and the prior art are such that the subject matter as a whole would have been obvious at the time the invention was made to a person having ordinary skill in the art to which said subject matter pertains. Patentability shall not be negatived by the manner in which the invention was made.

This application currently names joint inventors. In considering patentability of the claims under 35 U.S.C. 103(a), the examiner presumes that the subject matter of the various claims was commonly owned at the time any inventions covered therein were made absent any evidence to the contrary. Applicant is advised of the obligation under 37 CFR 1.56 to point out the inventor and invention dates of each claim that was not commonly owned at the time a later invention was made in order for the examiner to consider the applicability of 35 U.S.C. 103(c) and potential 35 U.S.C. 102(e), (f) or (g) prior art under 35 U.S.C. 103(a).

Claims 1, 11, 18, 32, 35, 52, 55, 61, 65-71, 86-92, and 100-102 are rejected under 35 U.S.C. 103(a) as being unpatentable over Yamazaki, EP 1 003 223 A2 in view of Karr et al., U.S. Patent 6,534,425 B1.

Yamazaki shows the invention substantially as claimed including forming a conductive film 108 over a semiconductor 102 with an insulating film 103 therebetween; forming a resist pattern 109 on the conductive film; forming a gate electrode 108 by a first etching using the resist pattern wherein a thickness of an edge portion of the gate electrode is smaller than a thickness of a middle portion of the gate electrode; and introducing an impurity element into the semiconductor with the gate electrode as a mask to form a first impurity region and a second impurity region in the semiconductor 102, wherein the first impurity region is not overlapped with the gate electrode and the second impurity region is overlapped with the edge portion of the gate electrode (see figs. 1A-4D and paragraphs 0031-0073).

Yamazaki fails to expressly disclose wherein a thickness of an edge portion of the resist pattern is smaller than a thickness of a middle portion of the resist pattern and where the etching to form the tapered gate electrode is performed by dry etching.

Karr et al. discloses a reticle with a diffraction grating in order to form a tapered photoresist which can be transferred to an underlying structure through dry etching (see abstract, figs. 3a-5b and col. 3-line 23 to col. 4-line 42). In view of this disclosure, it would have been obvious to one of ordinary skill in the art at the time the invention was made to modify the process of Yamazaki so as to use the reticle pattern and etching

process of Karr et al. because this is a suitable method in which to make a tapered gate electrode structure.

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Claims 4, 21, 33, 36, 53, 58, 72, 74-78, 93, and 95-99 are rejected under 35 U.S.C. 103(a) as being unpatentable over Yamazaki, EP 1 003 223 A2 in view of Karr et al., U.S. Patent 6,534,425 B1 as applied to claims 1, 11, 18, 32, 35, 52, 55, 61, 65-71, 86-92, and 100-102 above, and further in view of Tabata et al., U.S. Patent 5,744,381.

Yamazaki and Karr et al. are applied as above but fail to expressly disclose forming a reticle or a photoresist mask having a translucent film portion.

Tabata et al. discloses the use of a translucent mask such as silicon nitride for conventional chrome masks in photoresist applications (see col. 1-lines 58-64). In view of this disclosure, it would have been obvious to one of ordinary skill in the art at the time the invention was made to modify the process of Yamazaki modified by Karr et al. so as to use the translucent mask of Tabata et al. because such a mask will improve the resolution characteristic of the exposure apparatus.

Response to Arguments

Applicant's arguments filed 2/1/05 have been fully considered but they are not persuasive. Applicant argues that Yamazaki fails to show forming a resist pattern 109 on a conductive film and using the resist pattern to etch the conductive film to form a tapered electrode. However, it is clear from the figures and description in Yamazaki that the final gate electrode structure is made precisely as described by the examiner.

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The fact that the intermediate structure of the gate electrode is not in a tapered shape is not relevant to the claimed subject matter.

In response to applicant's arguments against the references individually, one cannot show nonobviousness by attacking references individually where the rejections are based on combinations of references. See *In re Keller*, 642 F.2d 413, 208 USPQ 871 (CCPA 1981); *In re Merck & Co.*, 800 F.2d 1091, 231 USPQ 375 (Fed. Cir. 1986).

In response to applicant's argument that there is no suggestion to combine the references, the examiner recognizes that obviousness can only be established by combining or modifying the teachings of the prior art to produce the claimed invention where there is some teaching, suggestion, or motivation to do so found either in the references themselves or in the knowledge generally available to one of ordinary skill in the art. See *In re Fine*, 837 F.2d 1071, 5 USPQ2d 1596 (Fed. Cir. 1988)and *In re Jones*, 958 F.2d 347, 21 USPQ2d 1941 (Fed. Cir. 1992). In this case, suitability for an intended purpose has been identified as a proper motivation to combine references (see MPEP 2144.07).

Allowable Subject Matter

Claims 14, 73, and 94 are objected to as being dependent on a rejected claim, but would be allowable if written in independent form to include all the limitations of the present independent claim.

Business Center (EBC) at 866-217-9197 (toll-free).

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Conclusion

Any inquiry concerning this communication or earlier communications from the examiner should be directed to Richard A. Booth whose telephone number is (571) 272-1668. The examiner can normally be reached on Monday-Thursday from 7:30-6:00.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Michael Lebentritt can be reached on (571) 272-1873. The fax phone number for the organization where this application or proceeding is assigned is 703-872-9306.

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see http://pair-direct.uspto.gov. Should you have questions on access to the Private PAIR system, contact the Electronic

Richard A. Booth Primary Examiner Art Unit 2812

April 5, 2005